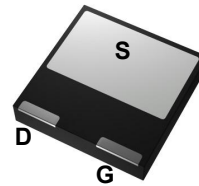
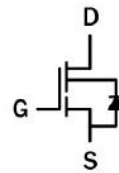


Features

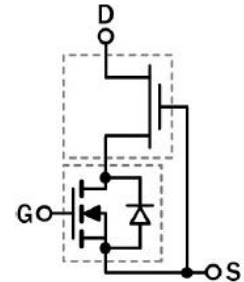
- 650V, 6.5A, $R_{DS(on)}(typ.) = 230m\Omega @ V_{GS} = 8V$.
- Very low Q_{RR}
- Reduced Crossover Loss
- Easy to drive with commonly-used gate drivers
- Enables AC-DC bridgeless totem-pole PFC designs
 - Increased power density
 - Reduced system size and weight
 - Overall lower system cost
- Achieves increased efficiency in both hard- and soft switched circuits



DFN8X8-3L
Bottom View



Cascode Schematic Symbol



Cascode Device Structure

Application

- Power adapters
- Low power SMPS
- Lighting

Absolute Maximum Ratings ($T_c = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter		Limit	Unit
V_{DS}	Drain-Source Voltage		650	V
$V_{(TR)DSS}$	Transient Drain to Source Voltage ^a		800	V
V_{GSS}	Gate-Source Voltage		± 18	V
P_D	Maximum power Dissipation @ $T_c = 25^\circ\text{C}$		21.6	W
I_D	Drain Current-Continuous	$T_c = 25^\circ\text{C}$ ^b	6.5	A
	Drain Current-Continuous	$T_c = 100^\circ\text{C}$ ^b	4.1	A
I_{DM}	Drain Current-Pulsed	Pulse Width = 10 μ s	30	A
T_c	Operating Temperature Case		-55 to +150	$^\circ\text{C}$
T_J	Operating Temperature Junction		-55 to +150	$^\circ\text{C}$
T_s	Storage Temperature		-55 to +150	$^\circ\text{C}$
T_{SOLD}	Soldering Peak Temperature ^c		260	$^\circ\text{C}$

Thermal Characteristics

Symbol	Parameter	Typical	Unit
$R_{\theta JC}$	Thermal Resistance Junction-Case	5.8	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ^d	52	$^\circ\text{C}/\text{W}$

Electrical Characteristics ($T_J = 25^\circ \text{C}$ unless otherwise noted)

■ Off Characteristics

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
$V_{(BL)DSS}$	Reverse Breakdown Voltage	$V_{GS} = 0V$	650	-	-	V
I_{DSS}	Reverse Leakage Current	$V_{GS} = 0V, V_{DS} = 650V$ $T_J = 25^\circ \text{C}$	-	1.0	10	μA
		$V_{GS} = 0V, V_{DS} = 650V$ $T_J = 150^\circ \text{C}$	-	2.0	-	μA
I_{GSS}	Gate-to-source Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 18V$	-	-	± 100	nA

■ On Characteristics

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 500\mu\text{A}$	1.6	2.1	2.6	V
$R_{DS(on)eff}$	On Resistance	$V_{GS} = 8V, I_D = 5A$ $T_J = 25^\circ \text{C}$	-	230	300	m Ω
		$V_{GS} = 8V, I_D = 5A$ $T_J = 150^\circ \text{C}$	-	405	-	

■ Dynamic Characteristics

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
C_{ISS}	Input Capacitance	$V_{GS} = 0V,$ $V_{DS} = 400V$ $f = 1\text{MHz}$	-	793	-	pF
C_{OSS}	Output Capacitance		-	33	-	
C_{RSS}	Transfer Capacitance		-	2.7	-	
$C_{o(er)}$	Output Capacitance, energy related	$V_{GS} = 0V,$ $V_{DS} = 0 \sim 400V$	-	99	-	pF
$C_{o(tr)}$	Output Capacitance, time related		-	71	-	

■ On Characteristics

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-On Delay Time	$V_{GS} = 0 \sim 8V,$ $V_{DS} = 400V,$ $I_D = 4A,$ $R_g = 30\Omega$	-	13	-	ns
t_r	Turn-On Rise Time		-	25	-	
$t_{d(off)}$	Turn-Off Delay Time		-	47	-	
t_f	Turn-Off Fall Time		-	34	-	
Q_G	Total Gate Charge	$V_{GS} = 0 \sim 8V,$ $V_{DS} = 400V,$ $I_D = 4A$	-	9.0	-	nC
Q_{GS}	Gate-Source Charge		-	1.6	-	
Q_{GD}	Gate-Drain Charge		-	2.4	-	
Q_{OSS}	Output Charge	$V_{GS} = 0V, V_{DS} = 0 \sim 400V$	-	28	-	nC



■ Drain-Source Diode Characteristics

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
I_S	Reverse Current	$V_{GS} = 0\text{ V}$	-	-	6.5	A
V_{SD}	Reverse Voltage	$V_{GS} = 0\text{ V}, I_S = 2\text{ A}$	-	1.2	-	V
		$V_{GS} = 0\text{ V}, I_S = 5\text{ A}$	-	2.0	-	V
t_{RR}	Reverse Recovery Time	$I_S = 5\text{ A}, V_{DS} = 400\text{ V},$ $di/dt = 200\text{ A}/\mu\text{s}$	-	14	-	ns
Q_{RR}	Reverse Recovery Charge		-	11	-	nC

Notes:

- a. In off-state, spike duty cycle $D < 0.01$, spike duration $< 1\mu\text{s}$.
- b. For increased stability at high current operation.
- c. Reflow MSL3.
- d. Device on one layer epoxy PCB for drain connection (vertical and without air stream cooling, with 6cm^2 copper area and $70\mu\text{m}$ thickness).

Typical Characteristics ($T_C = 25^\circ\text{C}$ unless otherwise noted)

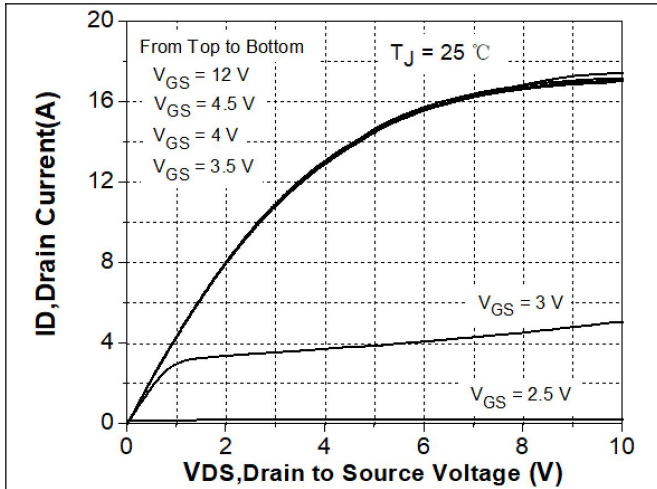


Figure 1. Typical Output Characteristics $T_J=25^\circ\text{C}$
Parameter: V_{GS}

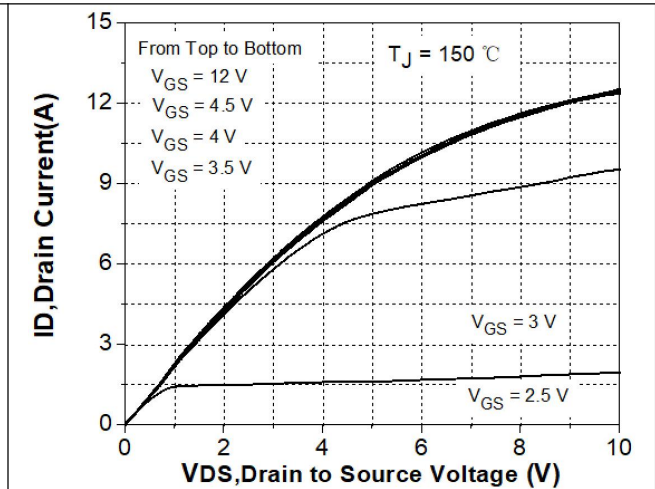


Figure 2. Typical Output Characteristics $T_J = 150^\circ\text{C}$
Parameter: V_{GS}

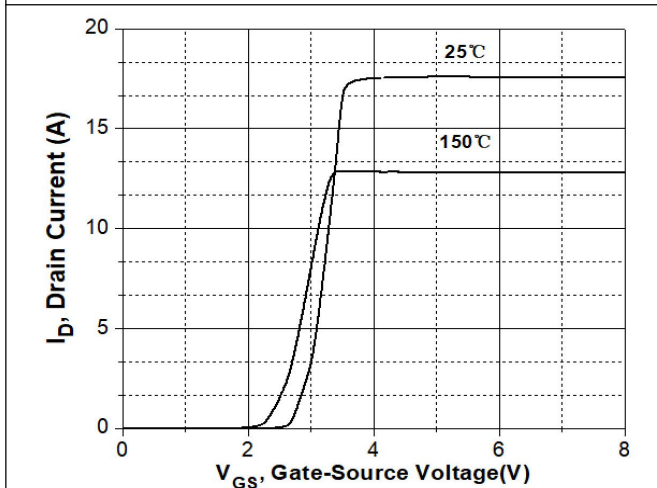


Figure 3. Typical Transfer Characteristics $V_{DS}=10\text{V}$
Parameter: T_J

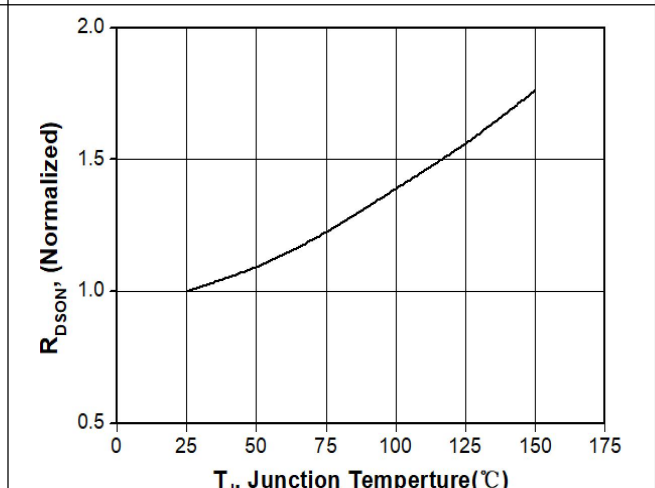


Figure 4. Normalized On-resistance
 $I_D = 16\text{ A}, V_{GS} = 10\text{ V}$

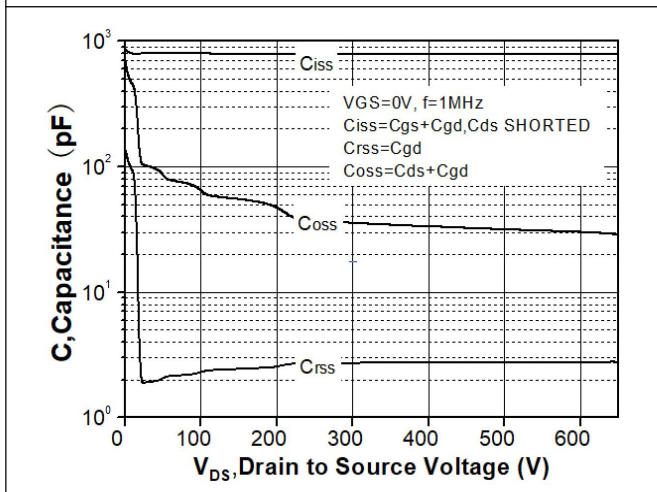


Figure 5. Typical Capacitance
 $V_{GS} = 0\text{V}, f = 1\text{MHz}$

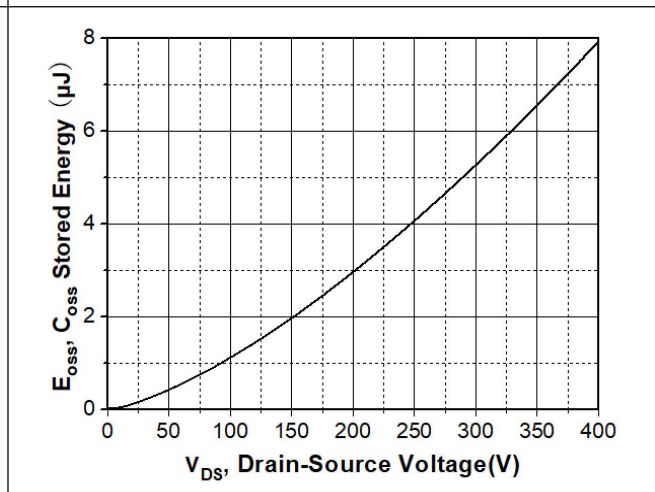


Figure 6. Typical C_{OSS} Stored Energy

Typical Characteristics ($T_C = 25^\circ\text{C}$ unless otherwise noted)

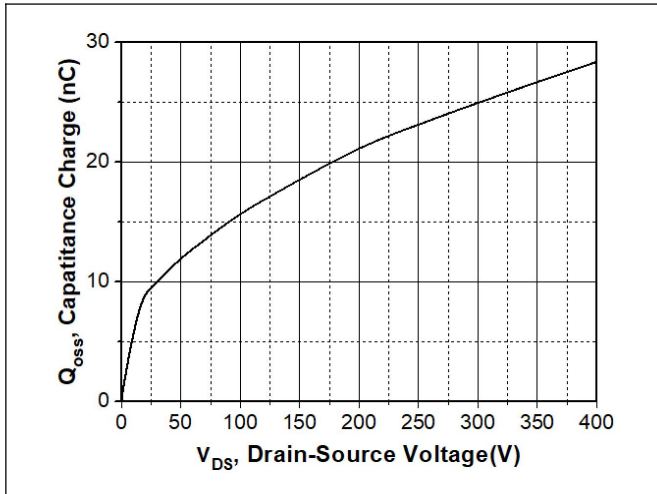


Figure 7. Typical Q_{oss}

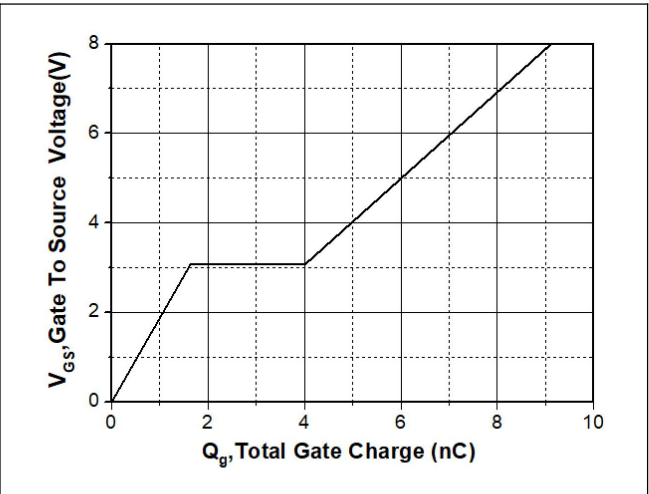


Figure 8. Typical Gate Charge

$I_{DS} = 10\text{A}, V_{DS} = 400\text{V}$

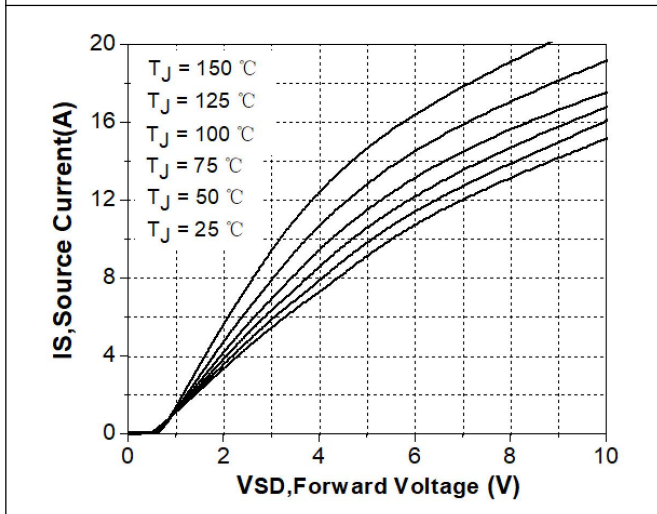


Figure 9. Forward Characteristics of Rev. Diode $I_S = f(V_{SD})$, Parameter T_J

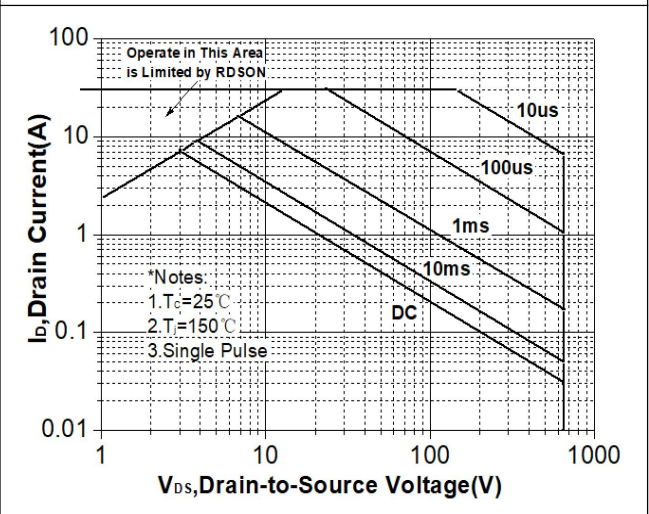


Figure 10. Safe Operating Area $T_C = 25^\circ\text{C}$ (calculated based on thermal limit)

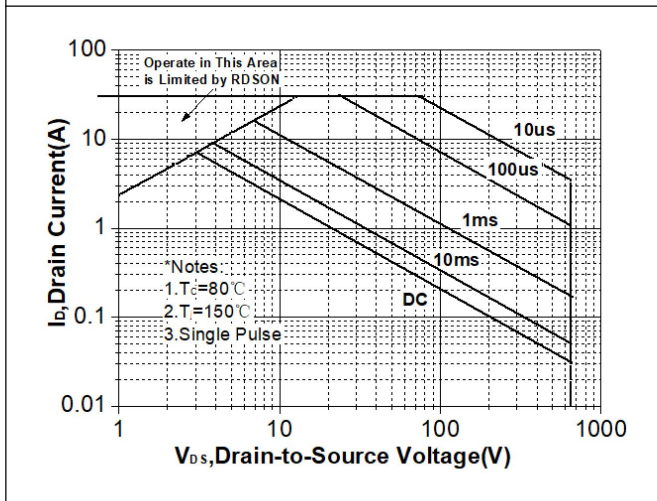


Figure 11. Safe Operating Area $T_C = 80^\circ\text{C}$ (calculated based on thermal limit)

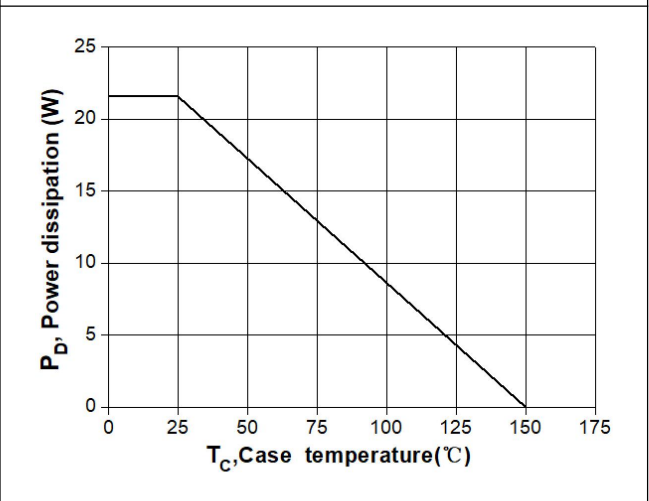


Figure 12. Power Dissipation

Typical Characteristics ($T_C = 25^\circ\text{C}$ unless otherwise noted)

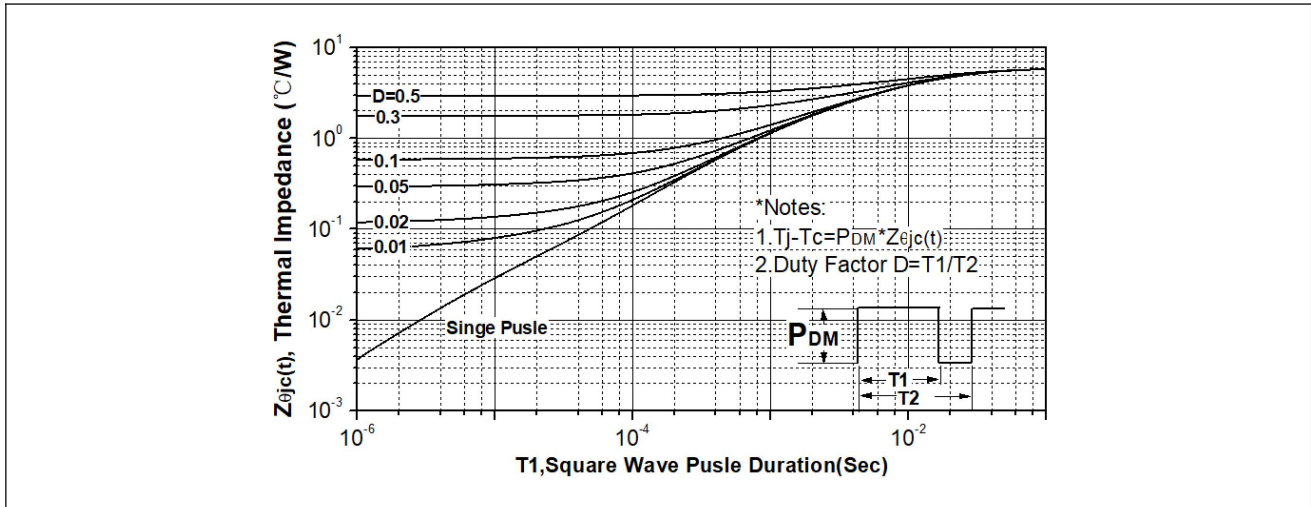


Figure 13. Transient Thermal Resistance

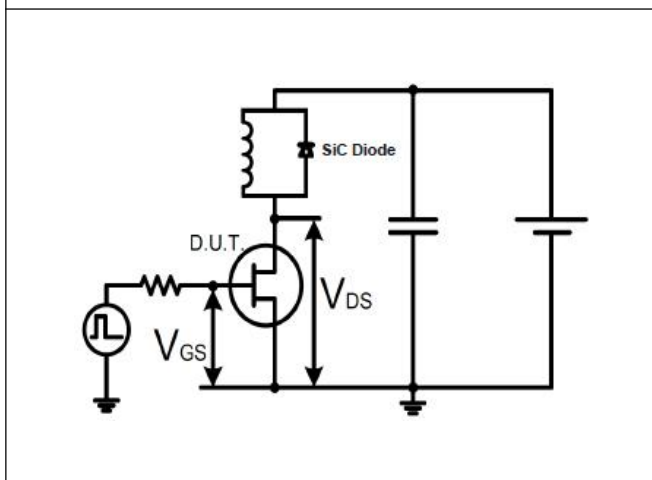


Figure 14. Switching Time Test Circuit

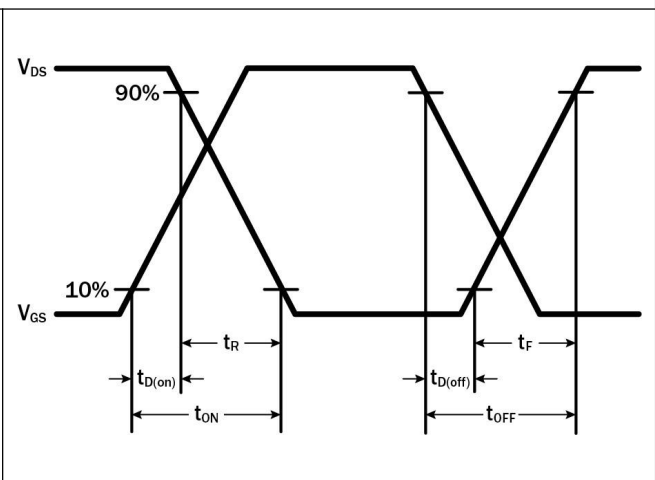


Figure 15. Switching Time Waveform

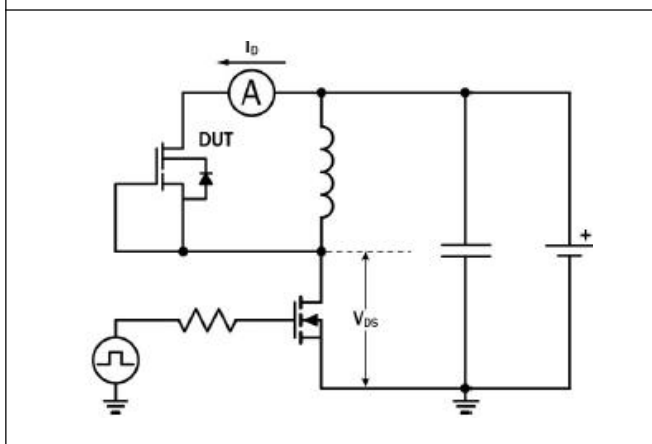


Figure 16. Diode Characteristics Test Circuit

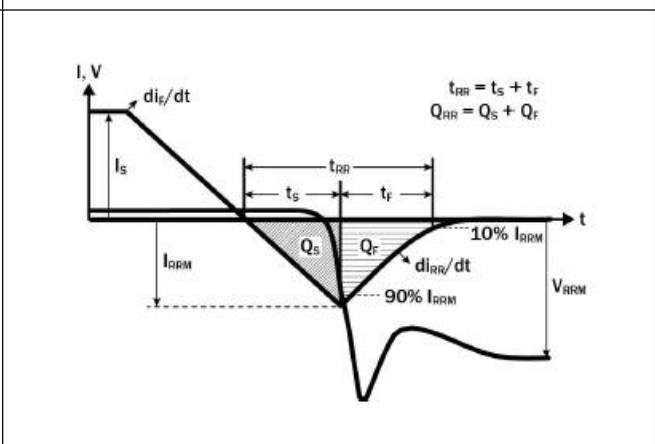
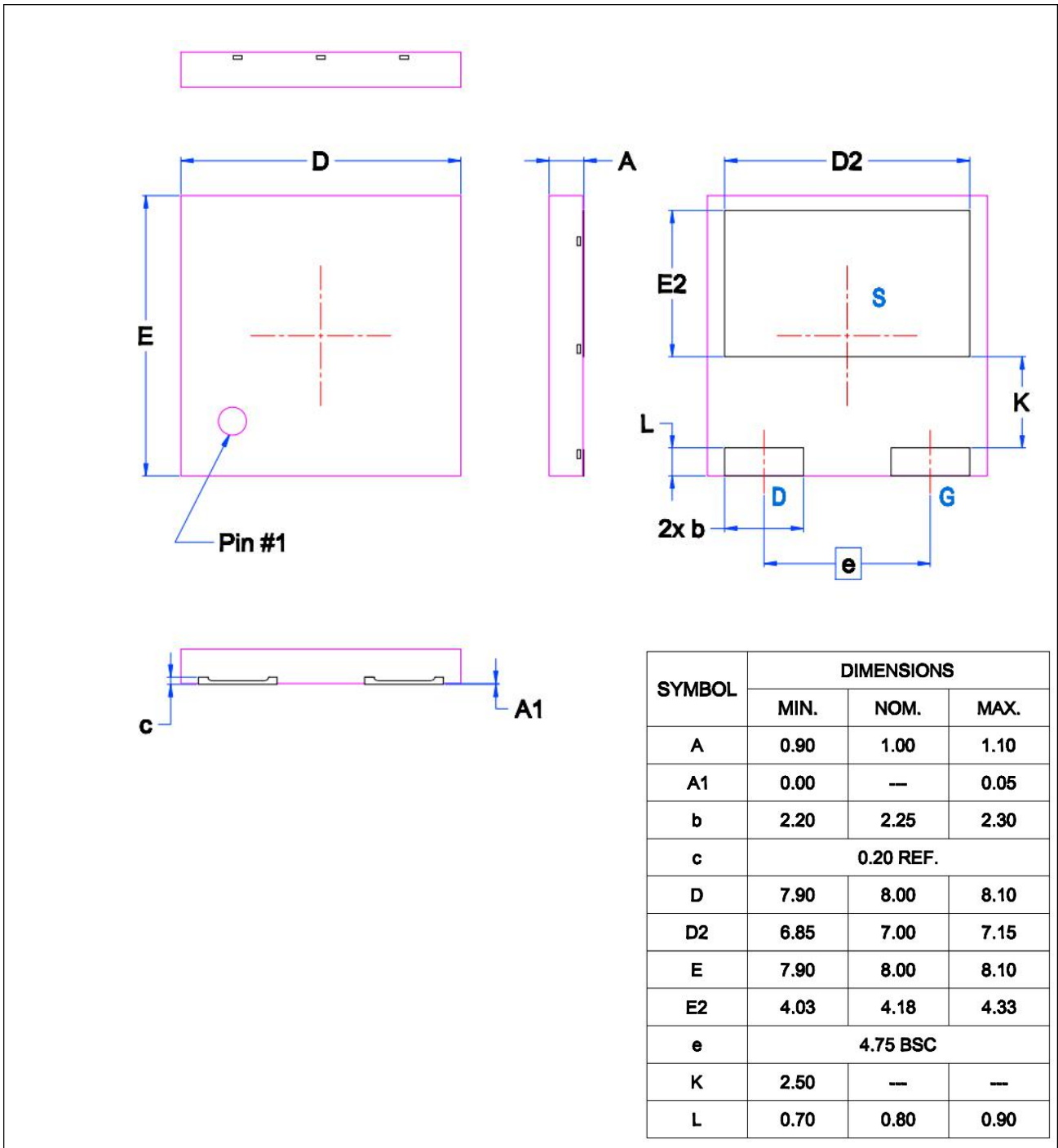


Figure 17. Diode Recovery Waveform

DFN8X8-3L Package Information



Revision History

Version	Date	Subjects (major changes since last revision)
0.1	2021-05-07	Preliminary Version
1.0	2021-12-10	Datasheet Complete